

NME8001H GaN TRANSISTOR

Document Number: NME8001H
Preliminary Datasheet V1.0

Gallium Nitride 28V 10W, RF Power Transistor



Description

The NME8001H is a 10W, GaN HEMT, designed for multiple applications with frequencies up to 8GHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical performance (on Innogration broadband band production fixture with device soldered)

NME8001H Vds=28V,Vgs=-2.47V,Idq=50mA, CW						
Freq(MHz)	Pin(dBm)	Pout(dBm)	Pout(W)	Ids(mA)	Gain(dB)	Eff(%)
6400	34.13	40.93	12.4	1078	6.8	41.0
6500	33.65	41.12	12.9	1017	7.5	45.4
6600	34.02	41.38	13.7	980	7.4	50.1
6700	33.39	41.26	13.4	914	7.9	52.2
6800	33.42	40.89	12.3	831	7.5	52.8
6900	33.26	40.54	11.3	791	7.3	51.1
7000	33.46	40.16	10.4	760	6.7	48.8
7100	33.54	40.3	10.7	789	6.8	48.5
7200	33.47	40.31	10.7	812	6.8	47.2

Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

1. Set VGS to the pinch--off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (28V)
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Table 1. Maximum Ratings (Not simultaneous, TC = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain--Source Voltage	V _{DSS}	150	Vdc
Gate--Source Voltage	V _{GS}	-10,+2	Vdc
Operating Voltage	V _{DD}	40	Vdc
Maximum Forward Gate Current	I _{gmax}	2.5	mA
Storage Temperature Range	T _{stg}	-65 to +150	°C
Case Operating Temperature	T _c	+150	°C

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Operating Junction Temperature(See note 1)	T_J	+200	$^{\circ}\text{C}$
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1. Continuous operation at maximum junction temperature will affect MTTF

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case $T_C=85^{\circ}\text{C}$, $T_J=200^{\circ}\text{C}$, DC Power Dissipation(See note 1)	$R_{\theta JC}$	8	C/W

1. $R_{\theta JC-DC}$ is tested at only DC condition, it is related to the highest thermal resistor value among all test conditions. It might be differently lower in different RF operation conditions like CW signal ,pulsed RF signal etc.

Table 3. Electrical Characteristics ($T_C = 25^{\circ}\text{C}$ unless otherwise noted)

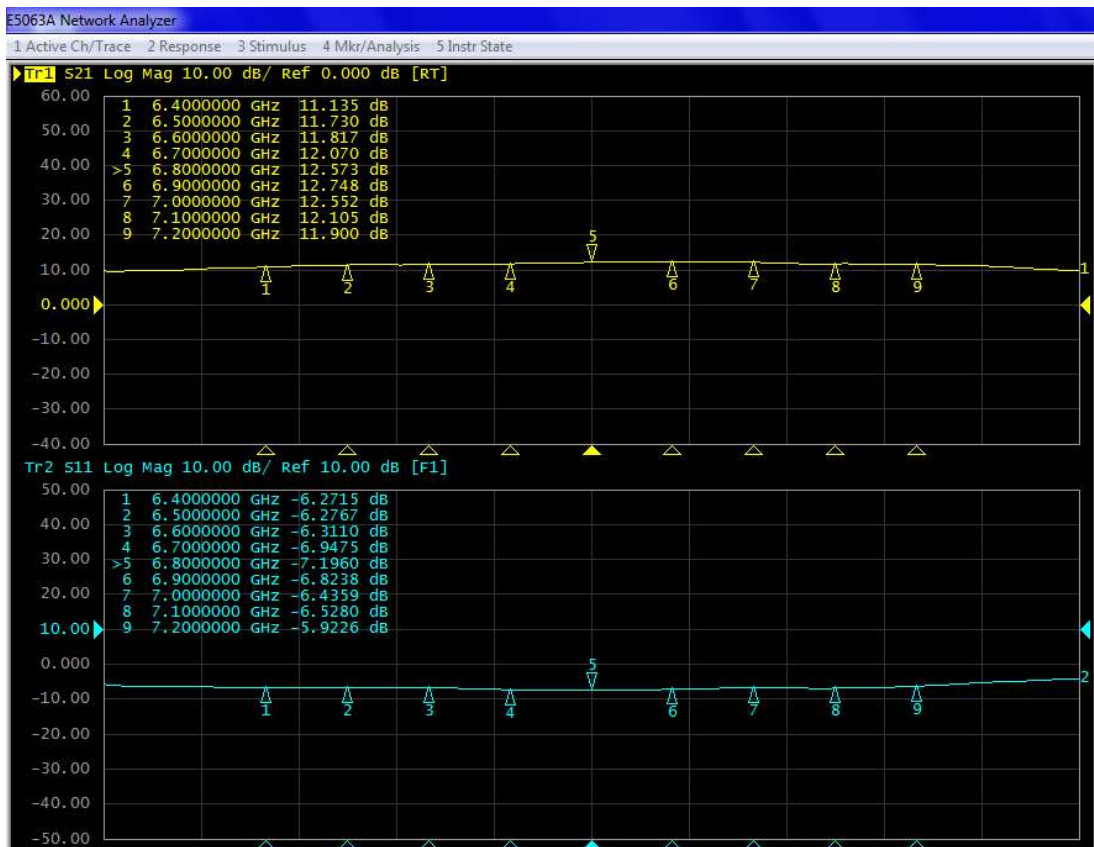
DC Characteristics

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{GS}=-8\text{V}$; $I_{DS}=2.5\text{mA}$	V_{DSS}	150			V
Gate Threshold Voltage	$V_{DS} = 28\text{V}$, $I_D = 2.5\text{mA}$	$V_{GS(th)}$		-2.7		V
Gate Quiescent Voltage	$V_{DS} = 28\text{V}$, $I_{DS}=50\text{mA}$, Measured in Functional Test	$V_{GS(Q)}$		-2.47		V

Typical performance

6.4-7.2GHz

Figure 3: Network analyzer output, S11 and S21 ($V_{DS}=28\text{V}$ $V_{GS}=-2.45\text{V}$ $I_{DQ}=50\text{mA}$)



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Package Outline

Flanged ceramic package; 2 leads

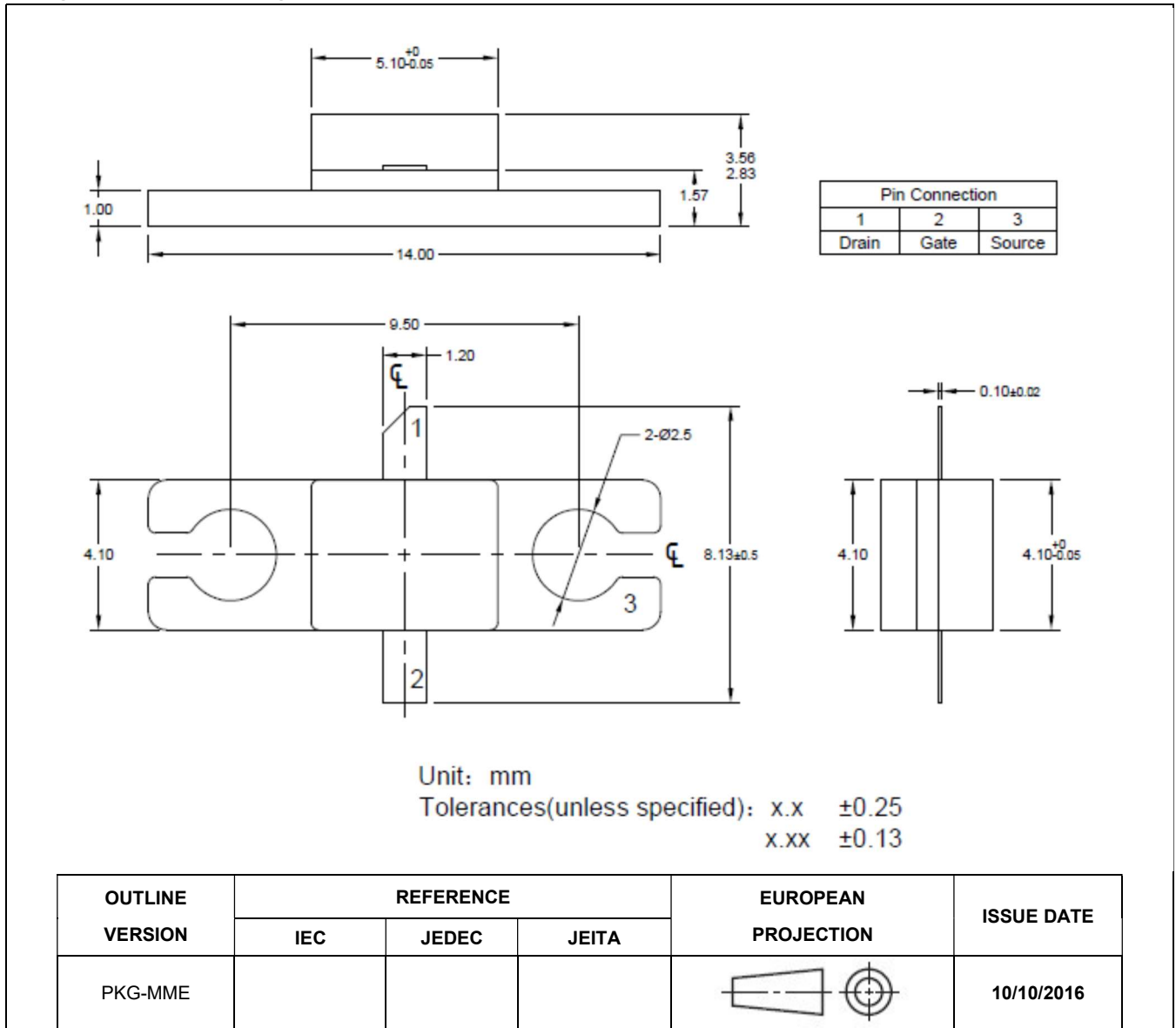


Figure 1. Package Outline PKG-MME

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Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2023/2/28	V1.0	Preliminary Datasheet

Application data based on RXT-23-05

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